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Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	80
Program Memory Size	768KB (768K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p54l5beaby

Table 2. SPC56xP54x/SPC56xP60x device comparison (continued)

	Feature	SPC560P54	SPC560P60	SPC56AP54	SPC56AP60		
Enhanced D	MA (direct memory nnels	16					
FlexRay			Yes (64 mes	sage buffer)			
FlexCAN (co	ontroller area network)		3 ⁽¹⁾),(2)			
Safety port			Yes (via third FI	exCAN module)			
FCCU (fault	collection and control unit)		Yes	s ⁽³⁾			
CTU (cross	triggering unit)		Ye	es			
eTimer chan	inels		2 >	< 6			
FlexPWM (p channels	ulse-width modulation)		N	lo			
Analog-to-di	gital converters (ADC)	One (10-bit, 27-channel) ⁽⁴⁾					
LINFlex mod	dules	2 (1 × Master/Slave, 1 × Master only) ⁽⁵⁾					
DSPI (deser interface) me	ial serial peripheral odules	5 ⁽⁶⁾					
CRC (cyclic	redundancy check) units		2	(7)			
JTAG interfa	ice		Ye	es			
Nexus port of	controller (NPC)		Yes (Lev	/el 2+) ⁽⁸⁾			
	Digital power supply ⁽⁹⁾	3.3 V	or 5 V single suppl	y with external trai	nsistor		
Cupply	Analog power supply		3.3 V	or 5 V			
Supply	Internal RC oscillator		16 1	MHz			
	External crystal oscillator		4–40	MHz			
Packages			LQFP100 LQFP144		LQFP100 LQFP144 LQFP176 ⁽¹⁰⁾		
Temperature	Standard ambient temperature		–40 to	125 °C			

- 1. Each FlexCAN module has 32 message buffers.
- 2. One FlexCAN module can act as a Safety Port with a bit rate as high as 7.5 Mbit/s.
- 3. Enhanced FCCU version.
- Same amount of ADC channels as on SPC560P44/50 not considering the internally connected ones. 26 channels on LQFP144 and 16 channels on LQFP100.
- 5. LinFlex_1 is Master Only.
- 6. Increased number of CS for DSPI_1.
- 7. Upgraded specification with addition of 8-bits polynomial (CRC-8 VDA CAN) support and 3rd context.
- 8. Improved debugging capability with data trace capability and increased Nexus throughput available on emulation package.
- 9. 3.3 V range and 5 V range correspond to different orderable parts.
- 10. Software development package only. Not available for production.



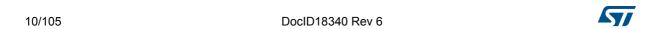
SPC56xP54x/SPC56xP60x is present on the market in two different options enabling different features: Full-featured, and Airbag configuration. *Table 3* shows the main differences between the two versions.

Table 3. SPC56xP54x/SPC56xP60x device configuration difference

Feature	Enhanced Full-featured	Full-featured	Airbag
FlexCAN (controller area network)	3	2	2
CTU (cross triggering unit)	Ye	es	No
FlexRay	Yes (64 mes	sage buffer)	No
DSPI (deserial serial peripheral interface) modules	ţ	5	4
CRC (cyclic redundancy check) unit	2	2	1

1.4 Block diagram

Figure 1 shows a top-level block diagram of the SPC56xP54x/SPC56xP60x MCU. *Table 4* summarizes the functions of the blocks.



The DSPI modules provide these features:

- Full duplex, synchronous transfers
- Master or slave operation
- Programmable master bit rates
- Programmable clock polarity and phase
- End-of-transmission interrupt flag
- Programmable transfer baud rate
- Programmable data frames from 4 to 16 bits
- Up to 28 chip select lines available
 - 8 each on DSPI 0 and DSPI 1
 - 4 each on DSPI 2, DSPI 3, and DSPI 4
- 8 clock and transfer attributes registers
- Chip select strobe available as alternate function on one of the chip select pins for deglitching
- FIFOs for buffering up to 5 transfers on the transmit and receive side
- Queueing operation possible through use of the eDMA
- General purpose I/O functionality on pins when not used for SPI

1.5.23 eTimer

Two eTimer modules are provided, each with six 16-bit general purpose up/down timer/counter per module. The following features are implemented:

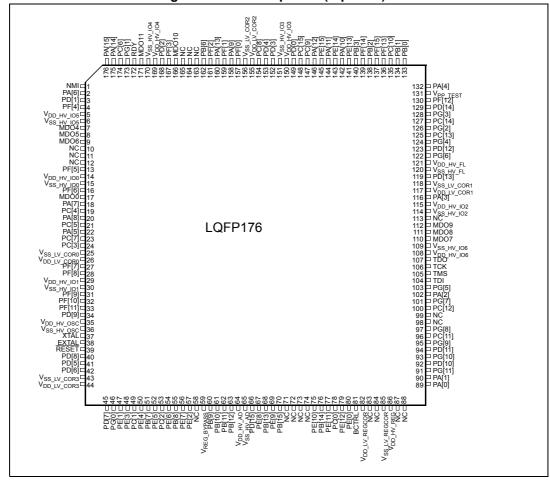
- Individual channel capability
 - Input capture trigger
 - Output compare
 - Double buffer (to capture rising edge and falling edge)
 - Separate prescaler for each counter
 - Selectable clock source
 - 0 % to 100% pulse measurement
 - Rotation direction flag (Quad decoder mode)
- Maximum count rate
 - Equals peripheral clock/2 for external event counting
 - Equals peripheral clock for internal clock counting
- Cascadeable counters
- Programmable count modulo
- Quadrature decode capabilities
- Counters can share available input pins
- Count once or repeatedly
- Preloadable counters
- Pins available as GPIO when timer functionality not in use

2 Package pinouts and signal descriptions

2.1 Package pinouts

The LQFP pinouts are shown in the following figures.

Figure 2. LQFP176 pinout (top view)^(b)



b. Software development package only. Not available for production.



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Table 5. Supply pins (continued)

	Supply		Pin	
Symbol	Description	LQFP 100	LQFP 144	LQFP 176 ⁽¹⁾
V _{DD_HV_REG} (3.3 V or 5.0 V)	Voltage regulator supply voltage	50	72	86
V _{DD_LV_REGCOR}	1.2 V decoupling ⁽²⁾ pins for core logic supply and voltage regulator feedback. Decoupling capacitor must be connected between this pins and V _{SS_LV_REGCOR} .	48	70	82
V _{SS_LV_REGCOR}	1.2 V decoupling ⁽²⁾ pins for core logic GND and voltage regulator feedback. Decoupling capacitor must be connected between this pins and V _{DD_LV_REGCOR} .	49	71	85
	ADC0 reference and supply voltage			
V _{DD_HV_AD}	ADC supply and high reference voltage	39	56	64
V _{SS_HV_AD}	ADC ground and low reference voltage	40	57	65
	Power supply pins (3.3 V or 5.0 V)	I.	I.	I.
V _{DD_HV_IO0}	Input/Output supply voltage	_	6	14
V _{SS_HV_IO0}	Input/Output ground	_	7	15
V _{DD_HV_IO1}	Input/Output supply voltage	13	21	29
V _{SS_HV_IO1}	Input/Output ground	14	22	30
V _{DD_HV_IO2}	Input/Output supply voltage	63	91	115
V _{SS_HV_IO2}	Input/Output ground	62	90	114
V _{DD_HV_IO3}	Input/Output supply voltage	87	126	150
V _{SS_HV_IO3}	Input/Output ground	88	127	151
V _{DD_HV_IO4}	Input/Output supply voltage	_	_	169
V _{SS_HV_IO4}	Input/Output ground	_	_	170
V _{DD_HV_IO5}	Input/Output supply voltage	_	_	5
V _{SS_HV_IO5}	Input/Output ground	_	_	6
V _{DD_HV_IO6}	Input/Output supply voltage	_	_	108
V _{SS_HV_IO6}	Input/Output ground	_	_	109
V _{DD_HV_FL}	Code and data flash supply voltage	69	97	121
V _{SS_HV_FL}	Code and data flash supply ground	68	96	120
V _{DD_HV_OSC}	Crystal oscillator amplifier supply voltage	16	27	35
V _{SS_HV_OSC}	Crystal oscillator amplifier ground	17	28	36
	Power supply pins (1.2 V)			
V _{DD_LV_COR0}	1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest $V_{SS_LV_COR0}$ pin.	12	18	26

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Pin Supply **LQFP LQFP LQFP Symbol** Description 176⁽¹⁾ 100 144 1.2 V Decoupling pins for core logic GND. Decoupling capacitor must be connected between these pins and the nearest 17 25 11 V_{SS LV COR0} V_{DD LV COR0} pin 1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest 65 93 117 V_{DD LV COR1} V_{SS_LV_COR1} pin. 1.2 V Decoupling pins for core logic GND. Decoupling capacitor must be connected between these pins and the nearest 118 66 94 V_{SS LV COR1} V_{DD_LV} COR1 pin. 1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest 92 131 155 V_{DD LV COR2} V_{SS LV COR2} pin. 1.2 V Decoupling pins for core logic GND. Decoupling capacitor must be connected between these pins and the nearest 93 132 156 V_{SS_LV_COR2} V_{DD_LV_COR 2} pin. 1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest 25 V_{DD LV COR3} 36 44 V_{SS LV COR3} pin. 1.2 V Decoupling pins for core logic GND. Decoupling capacitor must be connected between these pins and the nearest 35 24 43 V_{SS_LV_COR3} V_{DD_LV_COR 3} pin.

Table 5. Supply pins (continued)

2.2.2 System pins

Table 6 and *Table 7* contain information on pin functions for the SPC56xP54x/SPC56xP60x devices. The pins listed in *Table 6* are single-function pins. The pins shown in *Table 7* are multi-function pins, programmable via their respective Pad Configuration Register (PCR) values.

Table 6. System pins

Symbol	Description		Pad Speed ⁽¹⁾		Pin		
		Direction	SRC=0	SRC=1	LQFP 100	LQFP 144	LQFP 176 ⁽²⁾
	Dedicated	d pins					
MDO0	Nexus Message Data Output—line 0	Output Only	Fa	ıst	_	9	17
MDO4	Nexus Message Data Output—line 4	Output Only	Fast		_	_	7



^{1.} LQFP176 available only as development package.

^{2.} See datasheet Voltage Regulator Electrical Characteristics section for more details.

Table 6. System pins (continued)

	Table 6. System pi		Pad Sp	peed ⁽¹⁾	Pin		
Symbol	Description	Direction	SRC=0	SRC=1	LQFP 100	LQFP 144	LQFP 176 ⁽²⁾
MDO5	Nexus Message Data Output—line 5	Output Only	Fa	st	_	_	8
MDO6	Nexus Message Data Output—line 6	Output Only	Fa	st	_	_	9
MDO7	Nexus Message Data Output—line 7	Output Only	Fa	st	_	_	110
MDO8	Nexus Message Data Output—line 8	Output Only	Fa	st	_	_	111
MDO9	Nexus Message Data Output—line 9	Output Only	Fa	st	_	_	112
MDO10	Nexus Message Data Output—line 10	Output Only	Fa	st	_	_	166
MDO11	Nexus Message Data Output—line 11	Output Only	Fa	st	_	_	171
RDY	Nexus ready output	Output Only	_	_	_	_	172
NMI	Non-Maskable Interrupt	Input Only	_	_	1	1	1
XTAL	Analog output of the oscillator amplifier circuit. Needs to be grounded if oscillator is used in bypass mode.	_	_	_	18	29	37
EXTAL	Analog input of the oscillator amplifier circuit, when the oscillator is not in bypass mode. Analog input for the clock generator when the oscillator is in bypass mode.	_	_	_	19	30	38
TMS ⁽³⁾	JTAG state machine control	Input Only	_	_	59	87	105
TCK ⁽³⁾	JTAG clock	Input Only	_	1	60	88	106
TDI ⁽³⁾	JTAG data input	Input Only	_	1	58	86	104
TDO ⁽³⁾	JTAG data output	Output Only	_	-	61	89	107
	Reset	pin					
RESET ⁽⁴⁾	Bidirectional reset with Schmitt trigger characteristics and noise filter	Bidirection al	Medium	_	20	31	39
	Test p	in					
V _{PP TEST}	Pin for testing purpose only. To be tied to ground in normal operating mode.	_	_	_	74	107	131
V _{REG_BYPASS}	Pin for testing purpose only. To be tied to ground in normal operating mode.	_	_		34	51	59

^{1.} SRC values refer to the value assigned to the Slew Rate Control bits of the pad configuration register.



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3.3 Absolute maximum ratings

Table 9. Absolute maximum ratings⁽¹⁾

Symbol		Parameter	Conditions	Min Max ⁽²⁾		Unit
V _{SS_HV}	SR	Digital ground	_	0	0	V
V _{DD_HV_IOx} (3)	SR	3.3 V / 5.0 V input/output supply voltage with respect to ground (V _{SS_HV})	_	-0.3	6.0	V
V _{SS_HV_IOx}	SR	Input/output ground voltage with respect to ground (V _{SS_HV})	_	-0.1	0.1	٧
		3.3 V / 5.0 V code and data flash	_	-0.3	6.0	
V _{DD_HV_FL}	SR	memory supply voltage with respect to ground (V _{SS_HV})	Relative to V _{DD_HV_IOx}	-0.3	V _{DD_HV_IOx} + 0.3	V
V _{SS_HV_FL}	SR	Code and data flash memory ground with respect to ground (V _{SS_HV})	_	-0.1	0.1	V
		3.3 V / 5.0 V crystal oscillator	_	-0.3	6.0	
V _{DD_HV_OSC}	SR	amplifier supply voltage with respect to ground (V _{SS_HV})	Relative to V _{DD_HV_IOx}	-0.3	V _{DD_HV_IOx} + 0.3	V
V _{SS_HV_OSC}	SR	3.3 V / 5.0 V crystal oscillator amplifier reference voltage with respect to ground (V _{SS_HV})	_	-0.1	0.1	٧
		3.3 V / 5.0 V voltage regulator supply	_	- 0.3	6.0	
$V_{DD_HV_REG}$	SR	voltage with respect to ground (V _{SS_HV})	Relative to V _{DD_HV_IOx}	- 0.3	V _{DD_HV_IOx} + 0.3	V
V	SR	3.3 V / 5.0 V ADC supply and high reference voltage with respect to	V _{DD_HV_REG} < 2.7 V	- 0.3	V _{DD_HV_REG} + 0.3	V
V _{DD_HV_AD}	Six	ground (V _{SS_HV})	V _{DD_HV_REG} > 2.7 V	- 0.3	6.0	V
V _{SS_HV_AD}	SR	ADC ground and low reference voltage with respect to ground (V _{SS_HV})	_	-0.1	0.1	V
TV _{DD}	SR	Slope characteristics on all V _{DD} during power up ⁽⁴⁾ with respect to ground (V _{SS_HV})	_	3.0 ⁽⁵⁾	500 x 10 ³ (0.5 [V/µs])	V/s
		Voltage on any pin with respect to	_	-0.3	6.0	
V _{IN}	SR	ground (V _{SS_HV_IOx}) with respect to ground (V _{SS_HV})	Relative to V _{DD_HV_IOx}	-0.3	V _{DD_HV_IOx} + 0.3	V
V	SR	Analog input voltage	V _{DD_HV_REG} < 2.7 V	V _{SS_HV_AD} - 0.3	V _{DD_HV_AD} + 0.3	V
V _{INAN}	JIX	Analog input voltage	V _{DD_HV_REG} > 2.7 V	V _{SS_HV_AD}	V _{DD_HV_AD}	V
I _{INJPAD}	SR	Injected input current on any pin during overload condition	_	-10	10	mA



Max⁽¹⁾ **Conditions Symbol Parameter** Min Unit 3.0 3.6 3.3 V voltage regulator SR ٧ $V_{DD_HV_REG}$ Relative to supply voltage $V_{DD_HV_IOx} + 0.1$ $V_{DD_HV_IOx} - 0.1$ $V_{DD_HV_IOx}$ 3.0 5.5 3.3 V ADC supply and high SR ٧ V_{DD HV AD} Relative to reference voltage 5.5 V_{DD_HV_REG} – 0.1 $V_{DD_HV_REG}$ ADC ground and low $V_{SS_HV\ AD}$ SR 0 0 reference voltage $V_{DD_LV_REGCOR}^{(3),(4)}$ SR ٧ Internal supply voltage V_{SS LV REGCOR}(3) SR Internal reference voltage 0 0 ٧ $V_{DD_LV_CORx}^{-}$ SR Internal supply voltage V V_{SS_LV_CORx}⁽³⁾ ٧ 0 0 SR Internal reference voltage Ambient temperature under °C T_A SR -40 125 bias

Table 11. Recommended operating conditions (3.3 V) (continued)

Figure 7 shows the constraints of the different power supplies.



Parametric figures can be out of specification when voltage drops below 4.5 V, however, guaranteeing the full functionality. In particular, ADC electrical characteristics and I/Os DC electrical specification may not be guaranteed.

^{2.} The difference between each couple of voltage supplies must be less than 100 mV, $|V_{DD_HV_IOy} - V_{DD_HV_IOx}| < 100$ mV.

To be connected to emitter of external NPN. Low voltage supplies are not under user control—these are produced by an
on-chip voltage regulator—but for the device to function properly the low voltage grounds (V_{SS_LV_xxx}) must be shorted to
high voltage grounds (V_{SS_HV_xxx}) and the low voltage supply pins (V_{DD_LV_xxx}) must be connected to the external ballast
emitter.

^{4.} The low voltage supplies (V_{DD_LV_xxx}) are not all independent. V_{DD_LV_COR1} and V_{DD_LV_COR2} are shorted internally via double bonding connections with lines that provide the low voltage supply to the data flash memory module. Similarly, V_{SS_LV_COR1} and V_{SS_LV_COR2} are internally shorted. V_{DD_LV_REGCOR} and V_{DD_LV_REGCORx} are physically shorted internally, as are V_{SS_LV_REGCOR} and V_{SS_LV_CORx}.

SR

SR

SR

 C_{DEC2}

C_{DEC3}

L_{Req}

Value С **Conditions Symbol Parameter** Unit Min Max Тур Output voltage under ٧ V_{DD LV_REGCOR} CC Ρ maximum load run supply Post-trimming 1.15 1.32 current configuration BJT from Table 16. 3 capacitances (i.e. X7R or 19.5 30 μF X8R capacitors) with nominal External decoupling/stability C_{DEC1} SR value of 10 µF ceramic capacitor BJT BC817, one capacitance 14.3 22 μF of 22 µF BJT from Table 16. 3x10 µF. Resulting ESR of all three Absolute maximum value 50 $\text{m}\Omega$ capacitors of CDEC1 between 100 kHz and 10 MHz SR **RREG** BJT BC817, 1x 22 µF. Resulting ESR of the unique Absolute maximum value 10 40 $\mathsf{m}\Omega$ capacitor C_{DEC1} between 100 kHz and 10 MHz 4 capacitances (i.e. X7R or

Table 17. Voltage regulator electrical characteristics

3.8.2 Voltage monitor electrical characteristics

External decoupling/stability

External decoupling/stability

Resulting ESL of $V_{DD\ HV\ REG}$

BCTRL and V_{DD LV CORx} pins

ceramic capacitor

ceramic capacitor on

V_{DD HV REG}

The device implements a Power On Reset module to ensure correct power-up initialization, as well as three low voltage detectors to monitor the V_{DD} and the V_{DD LV} voltage while device is supplied:

C_{DEC1}

X8R capacitors) with nominal

3 capacitances (i.e. X7R or X8R capacitors) with nominal

value of 10 μ F; C_{DEC3} has to

be equal or greater than

value of 440 nF

1200

19.5

1760

30

nF

μF

nΗ

15

- POR monitors V_{DD} during the power-up phase to ensure device is maintained in a safe reset state
- LVDHV3 monitors V_{DD} to ensure device reset below minimum functional supply
- LVDHV5 monitors V_{DD} when application uses device in the 5.0V \pm 10% range
- LVDLVCOR monitors low voltage digital power domain

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3.11.2 DC electrical characteristics (3.3 V)

Table 22 gives the DC electrical characteristics at 3.3 V (3.0 V < $V_{DD_HV_IOX}$ < 3.6 V, NVUSRO[PAD3V5V]=1) as described in *Figure 14*.

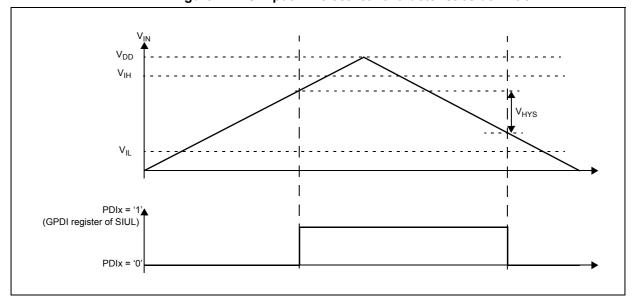


Figure 14. I/O input DC electrical characteristics definition

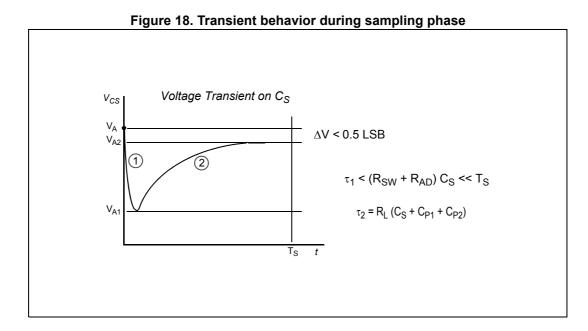
Table 22. DC electrical characteristics (3.3 V, NVUSRO[PAD3V5V]=1)⁽¹⁾

Symbo	I	Parameter	Conditions	Min	Max	Unit
V _{IL}	D	Minimum low level input voltage	_	-0.1 ⁽²⁾	_	V
V _{IL}	Р	Maximum low level input voltage	_	_	0.35 V _{DD_HV_IOx}	V
V _{IH}	Р	Minimum high level input voltage	_	0.65 V _{DD_HV_IOx}	_	V
V _{IH}	D	Maximum high level input voltage	_	_	$V_{DD_HV_IOx} + 0.1^{(2)}$	V
V _{HYS}	Т	Schmitt trigger hysteresis	_	0.1 V _{DD_HV_IOx}	_	V
V _{OL_S}	Р	Slow, low level output voltage	I _{OL} = 1.5 mA	_	0.5	V
V _{OH_S}	Ρ	Slow, high level output voltage	$I_{OH} = -1.5 \text{ mA}$	$V_{DD_HV_IOx} - 0.8$		V
V _{OL_M}	Р	Medium, low level output voltage	I _{OL} = 2 mA	_	0.5	٧
V _{OH_M}	Р	Medium, high level output voltage	I _{OH} = -2 mA	$V_{DD_HV_IOx} - 0.8$	_	V
V _{OL_F}	Р	Fast, high level output voltage	I _{OL} = 11 mA	_	0.5	V
V _{OH_F}	Р	Fast, high level output voltage	I _{OH} = -11 mA	$V_{DD_HV_IOx} - 0.8$	_	V
V _{OL_SYM}	Р	Symmetric, high level output voltage	I _{OL} = 1.5 mA	_	0.5	٧
V _{OH_SYM}	Ρ	Symmetric, high level output voltage	I _{OH} = -1.5 mA	V _{DD_HV_IOx} – 0.8	1	٧
la	Р	Equivalent pull-up current	$V_{IN} = V_{IL}$	-130		μA
I _{PU}	•	Legarvaioni paii-ap canent	$V_{IN} = V_{IH}$	_	-10	μΛ

INTERNAL CIRCUIT SCHEME **EXTERNAL CIRCUIT** Channel Extended Sampling Selection Switch Source Filter **Current Limiter** \triangle R_S: Source impedance R_F: Filter resistance C_F: Filter capacitance R_L: Current limiter resistance R_{SW1} : Channel selection switch impedance (two contributions, R_{SW1} and R_{SW2}) R_{AD}: Sampling switch impedance $C_{P}\!\!:$ Pin capacitance (two contributions, $C_{P1},\,C_{P2}$ and $C_{P3})$ C_S: Sampling capacitance

Figure 17. Input equivalent circuit (extended channels)

A second aspect involving the capacitance network shall be considered. Assuming the three capacitances C_F , C_{P1} and C_{P2} are initially charged at the source voltage V_A (refer to the equivalent circuit reported in *Figure 16*): A charge sharing phenomenon is installed when the sampling phase is started (A/D switch close).



5

Symbo	Symbol Parameter Conditions ⁽¹⁾ Min		Conditions(1)		Value		Unit
Symbo			Тур	Max	Oilit		
TUE	Т	Total unadjusted error with current injection	16 precision channels	-3	_	3	LSB
TUE	Т	Total unadjusted error with current injection	10 standard channels	-4	_	4	LSB

Table 32. ADC conversion characteristics (continued)

- V_{DD} = 3.3 V to 3.6 V / 4.5 V to 5.5 V, T_A = -40 °C to T_{A MAX}, unless otherwise specified and analog input voltage from V_{SS_HV_AD} to V_{DD_HV_AD}.
- V_{INAN} may exceed V_{SS_ADC} and V_{DD_ADC} limits, remaining on absolute maximum ratings, but the results of the conversion will be clamped respectively to 0x000 or 0x3FF.
- 3. AD_clk clock is always half of the ADC module input clock defined via the auxiliary clock divider for the ADC.
- 4. When configured to allow 60 MHz ADC, the minimum ADC clock speed is 9 MHz, below which precision is lost.
- 5. During the sample time the input capacitance CS can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_{ADC_S}. After the end of the sample time t_{ADC_S}, changes of the analog input voltage have no effect on the conversion result. Values for the sample clock t_{ADC_S} depend on programming.
- 6. This parameter includes the sample time $t_{ADC\ S}$.
- 7. 20 MHz ADC clock. Specific prescaler is programmed on MC PLL CLK to provide 20 MHz clock to the ADC.
- 8. See Figure 16.

3.16 Flash memory electrical characteristics

Table 33. Program and erase specifications

				Value				
Symbol		Parameter Conditions		Min	Typ ⁽¹⁾	Initial max ⁽²⁾	Max ⁽³⁾	Unit
T _{wprogram}	Р	Word Program (32 bits) Time ⁽⁴⁾	Data Flash	_	30	70	500	μs
T _{dwprogram}	Р	Double Word (64 bits) Program Time ⁽⁴⁾	Code Flash	_	18	50	500	μs
Tayana	Р	Bank Program (64 KB) ^{(4), (5)}	Data Flash	_	0.49	1.2	4.1	s
T _{BKPRG}	Р	Bank Program (1056 KB) ^{(4), (5)}	Code Flash	_	2.6	6.6	66	s
T _{MDPRG}	Р	Module Program (512 KB) ⁽⁴⁾	Code Flash	_	1.3	1.65	33	S
T	Р	16 KB Block Pre-program and Erase Time	Code Flash		200	500	5000	ms
T _{16kpperase}	'	To No block Tre-program and Erase Time	Data Flash		700	800	3000	1113
T _{32kpperase}	Р	32 KB Block Pre-program and Erase Time	Code Flash	_	300	600	5000	ms
T _{64kpperase}	Р	64 KB Block Pre-program and Erase Time	Code Flash	_	400	900	5000	ms
T _{128kpperase}	Р	128 KB Block Pre-program and Erase Time	Code Flash	_	600	1300	5000	ms
t	Р	P Erase Suspend Request Rate ⁽⁶⁾	Code Flash	20				ms
t _{ESRT}	Р		Data Flash	10		_		1113

Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.

^{2.} Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.



- The maximum program and erase times occur after the specified number of program/erase cycles. These maximum values are characterized but not guaranteed.
- 4. Actual hardware programming times. This does not include software overhead.
- Typical bank programming time assumes that all cells are programmed in a single pulse. In reality some cells will require more than one pulse, adding a small overhead to total bank programming time (see Initial Max column).
- 6. Time between erase suspend resume and next erase suspend.

Table 34. Flash memory module life

Cumbo		Parameter	Conditions	Val	ue	Unit
Symbo	ı	Parameter	Conditions	Min	Тур	Unit
P/E	С	Number of program/erase cycles per block for 16 KB blocks over the operating temperature range (T _J)	_	100000	100000	cycles
P/E	O	Number of program/erase cycles per block for 32 KB blocks over the operating temperature range (T _J)	_	10000	100000	cycles
P/E	O	Number of program/erase cycles per block for 64 KB blocks over the operating temperature range (T _J)	_	10000	100000	cycles
P/E	С	Number of program/erase cycles per block for 128 KB blocks over the operating temperature range (T _J)	_	1000	100000	cycles
			Blocks with 0 – 1000 P/E cycles	20	_	years
Retention	С	Minimum data retention at 85 °C average ambient temperature ⁽¹⁾	Blocks with 10000 P/E cycles	10	_	years
			Blocks with 100000 P/E cycles	5	_	years

Ambient temperature averaged over duration of application, not to exceed recommended product operating temperature range.

Table 35. Flash read access timing

Symbol	С	Parameter Conditions ⁽¹⁾		Max	Unit
Fmax	С	Maximum working frequency for Code Flash	2 wait states	66	MHz
Tillax		at given number of WS in worst conditions	0 wait states	22	1011 12
Fmax	С	Maximum working frequency for Data Flash at given number of WS in worst conditions	8 wait states	66	MHz

^{1.} VDD = $3.3 \text{ V} \pm 10\% / 5.0 \text{ V} \pm 10\%$, TA = $-40 \text{ to } 125 \,^{\circ}\text{C}$, unless otherwise specified.



3.17 AC specifications

3.17.1 Pad AC specifications

Table 36. Output pin transition times

Symbol		С	Parameter	Conditions ⁽¹⁾			Value		
		J	raiametei	Conditions		Min	Тур	Max	Unit
T _{tr}	СС	D	Output transition time output pin ⁽²⁾ SLOW configuration	C _L = 25 pF	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	_	_	50	
		Т		C _L = 50 pF		_	_	100	
		D		C _L = 100 pF		_	_	125	ns
		D		C _L = 25 pF			_	40	
		Т		C _L = 50 pF	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	_	50	
		D		C _L = 100 pF			_	75	
		D	Output transition time output pin ⁽²⁾	C _L = 25 pF	V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	_	10	- ns
T _{tr} (СС	Т		C _L = 50 pF		_	_	20	
		C D		C _L = 100 pF		_	_	40	
			MEDIUM configuration	C _L = 25 pF		_	_	12	
		Т		C _L = 50 pF		_	_	25	
		D		C _L = 100 pF		_	_	40	
T _{tr}	CC	C D	Output transition time output pin ⁽²⁾ FAST configuration	C _L = 25 pF	SIUL.PCRx.SRC = 1 V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	_	4	
				C _L = 50 pF		_	_	6	
				C _L = 100 pF		_	_	12	ne
				C _L = 25 pF		_	_	4	ns
				C _L = 50 pF		_	7		
				C _L = 100 pF	SIUL.PCRx.SRC = 1	_	_	12]
T _{sim} (3)	CC	Т	Symmetric, same drive strength	V _{DD} = 5.0 V	± 10%, PAD3V5V = 0	_	_	4	ns
'sim` '			between N and P trai	between N and P transistor	$V_{DD} = 3.3 \text{ V}$	± 10%, PAD3V5V = 1	_	_	5

^{1.} V_{DD} = 3.3 V ± 10% / 5.0 V ± 10%, T_A = -40 °C to $T_{A\ MAX}$, unless otherwise specified.

3.18 AC timing characteristics

3.18.1 RESET pin characteristics

The SPC56xP54x/SPC56xP60x implements a dedicated bidirectional RESET pin.

^{2.} C_L includes device and package capacitances (C_{PKG} < 5 pF).

^{3.} Transition timing of both positive and negative slopes will differ maximum 50 %.

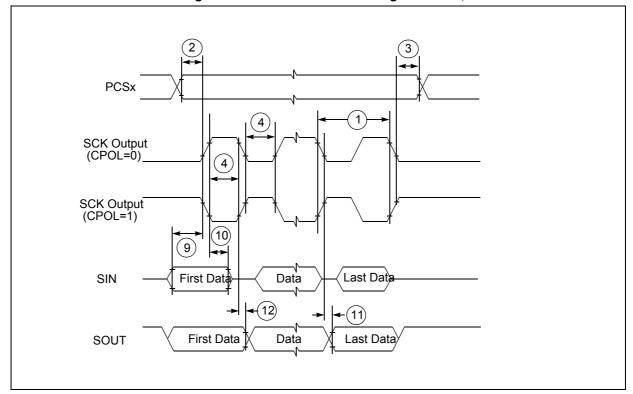
Figure 23. JTAG test access port timing

Table 41. DSPI timing⁽¹⁾ (continued)

No.	Syml	bol C		Parameter	Conditions	Min	Max	Unit	
			CC D	Data hold time for outputs	Master (MTFE = 0)	-2	_		
12		dO CC D Data			Slave	6	_	200	
12	ίнο			Data fiold time for outputs	Master (MTFE = 1, CPHA = 0)	6	_	ns	
					Master (MTFE = 1, CPHA = 1)	-2	_		

^{1.} All timing are provided with 50pF capacitance on output, 1ns transition time on input signal

Figure 29. DSPI classic SPI timing — master, CPHA = 0



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Table 42. LQFP144 mechanical data

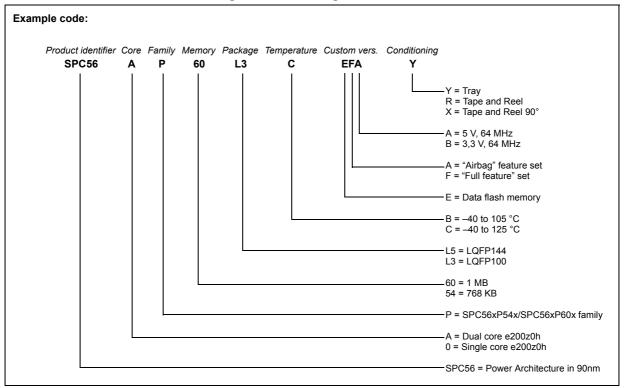
Symphol		mm		inches ⁽¹⁾			
Symbol	Min	Тур	Max	Min	Тур	Max	
А	_	_	1.600	_	_	0.0630	
A1	0.050	_	0.150	0.0020	_	0.0059	
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571	
b	0.170	0.220	0.270	0.0067	0.0087	0.0106	
С	0.090	_	0.200	0.0035	_	0.0079	
D	21.800	22.000	22.200	0.8583	0.8661	0.8740	
D1	19.800	20.000	20.200	0.7795	0.7874	0.7953	
D3	_	17.500	_	_	0.6890	_	
E	21.800	22.000	22.200	0.8583	0.8661	0.8740	
E1	19.800	20.000	20.200	0.7795	0.7874	0.7953	
E3	_	17.500	_	_	0.6890	_	
е	_	0.500	_	_	0.0197	_	
L	0.450	0.600	0.750	0.0177	0.0236	0.0295	
L1	_	1.000	_	_	0.0394	_	
k	0.0 °	3.5 °	7.0°	3.5 °	0.0 °	7.0 °	
ccc ⁽²⁾	0.080			0.0031			

^{1.} Values in inches are converted from mm and rounded to 4 decimal digits.

^{2.} Tolerance.

5 Ordering information

Figure 40. Ordering information scheme^(h)



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h. Not all configurations are available on the market. Please contact your ST sales representative to get the list of orderable commercial part number.

6 Revision history

Table 44 summarizes revisions to this document.

Table 44. Document revision history

Date	Revision	Substantive changes
21-Dec-2010	1	Initial release
18-Oct-2011	2	In the Feature list: Revised the first bullet. Changed "Up to 82 GPIO" to "Up to 80 GPIO" Changed "FlexRay module" to "1 FlexRay™ module". Added Section 1.5: Feature details Table 4: SPC56xP54x/SPC56xP60x series block summary, added FlexRay entry. In the "LQFP176 pinout (top view)" figure: − Pin 104 now is TDI, was PB[5] − Pin 107 now is TDO, was PB[4] − Pin 71 now is NC, was OKOUT − Pin 72 now is NC, was OKOUT − Pin 88 now is NC, was OKOUT − Pin 88 now is NC, was IPP_LIVI_B_VDDIO Table 7: Pin muxing: PB[6] was clk_out_div5, is now clk_out_div256 Removed PB[4] and PB[5] rows In the A[3] row, changed ABS[2] to ABS[1] Section 3.11: DC electrical characteristics, added "Peripherals supply current (5 V and 3.3 V)" table Table 14: EMI testing specifications, removed all references to SAE Replaced both Table 12: Thermal characteristics for 144-pin LQFP and Table 30: PLLMRFM electrical specifications (V _{DDPLL} = 1.08 V to 1.32 V, V _{SS} = V _{SSPLL} = 0 V, TA = TL to TH), changed the max value of f _{SYS} from 120 to 64 Table 33: Program and erase specifications: Removed all TBC changed the initial max value of T _{BKPRG} (Code Flash) from 3.3 to 6.6 s changed the max value of T _{BKPRG} (Data Flash) from 3.0 to 500 μs Added t _{ESRT} row Table 17: Voltage regulator electrical characteristics, updated V _{DD_L} v _{REGCOR} values Updated Table 18: Low voltage monitor electrical characteristics Updated Table 18: Low voltage monitor electrical characteristics Updated Table 21: Supply current (5.0 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.3 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.4 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.5 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.6 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.8 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.8 V, NVUSRO[PAD3V5V]=0) and Table 23: Supply current (3.8 V, NVUSRO[PAD3V5V]=0)

